

SiCPAK™ Product Family



World's Only Trench-Assisted Planar SiC Technology



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Technology
Partner



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SiCPAK was developed to
withstand harsh environments and
extreme operating conditions

for customers who require
stable and long-lasting performance
in demanding applications

Unparalleled Reliability and Efficient High-Temperature Performance

- ✓ **Performance: GeneSiC Trench Assisted Planar SiC MOSFET Technology**
 - Up to 20% lower $R_{DS,ON}$ at elevated temperature
 - Up to 15% lower switching losses
 - Unparalleled reliability under high-voltage/high-temperature/humidity/high-dVdt

- ✓ **Endurance: Epoxy-resin Potting Technology**
 - >10x improved temperature cycling reliability and most-stable thermal resistance
 - Protected against moisture ingress in humid environments

- ✓ **Designed to Address Mission-Profiles of Demanding Applications:**
 - EV roadside fast chargers, industrial welding, induction heating, industrial motor drives, solar inverters, and energy storage systems (ESS).

SiCPAK™ : Built for Endurance and Performance



SiCPAK F Series
(33.8mmX 62.8mm)

SiCPAK G Series
(56.7mm X 62.8mm)

R_{DS(ON)} @ V _G = 18V	Half-Bridge (2-Pack / Phase-Leg)	Full-Bridge (4-Pack)	Half-Bridge (2-Pack / Phase-Leg)	Full-Bridge (4-Pack)	3L-T-NPC
1200V 4.6 mΩ			G3F05MT12GB2 G3F05MT12GB2-T		
1200V 9.3 mΩ	G3F09MT12FB2 G3F09MT12FB2-T			G3F09MT12GB4 G3F09MT12GB4-T	<i>Qualification Samples</i>
1200V 17.0 mΩ	G3F17MT12FB2 G3F17MT12FB2-T				
1200V 18.5mΩ		G3F18MT12FB4 G3F18MT12FB4-T			

- -T Pre-Applied Thermal Interface Material (Honeywell PTM6000)
- All Pin-to-Pin Compatible with Industry Standard Press-fit Modules
- Built-in NTC thermistors

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Better Reliability Than Standard Press-Fit Modules Navitas

Reliability Improvements	SiCPAK™ Qualification	Competitor Qualification
Temperature Cycling (-55°C to 150°C)	1000 cycles	<100 cycles
Thermal Shock Test (-40°C to 125°C)	1000 cycles	<100 cycles
Temperature Humidity Bias (THB / HV-H3TRB)	1000 hrs 80% V_{DS} THB at module-level 1000 hrs 100% V_{DS} HV-H3TRB die-level	1000 hrs 80% V_{DS} die-level only

Navitas' Epoxy-Potted SiCPAK Modules **vs.** Competitors' Silicone-Gel Filled Modules after 1000 cycles of Thermal Shock

- Up to 15% thermal resistance increase for epoxy-resin vs. 33%-80% for silicone-gel
- All epoxy-resin potted modules passed isolation tests; all silicone-gel modules failed

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Thermal Shock Testing (-40°C to 125°C)

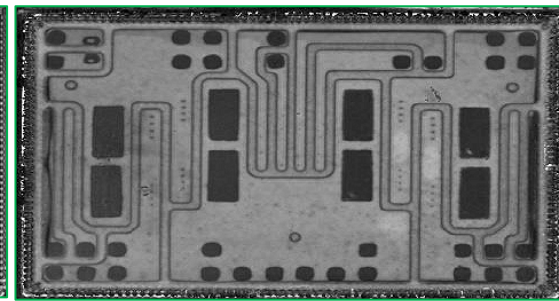
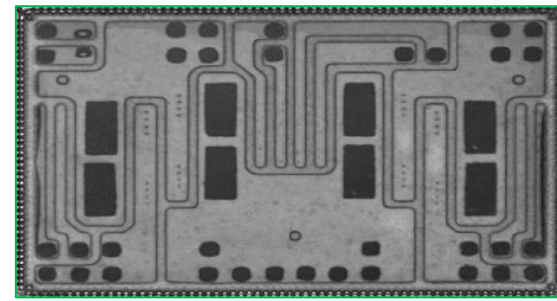
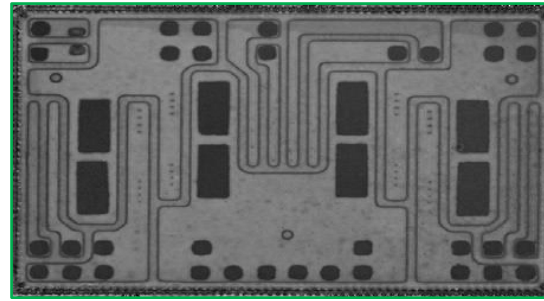
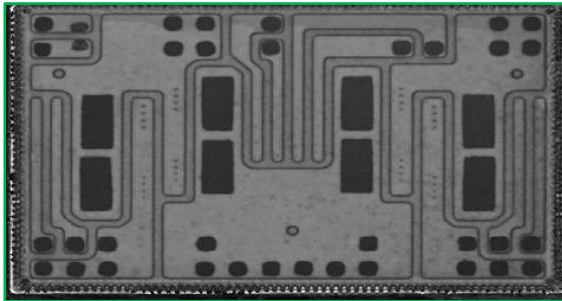
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100 Cycles

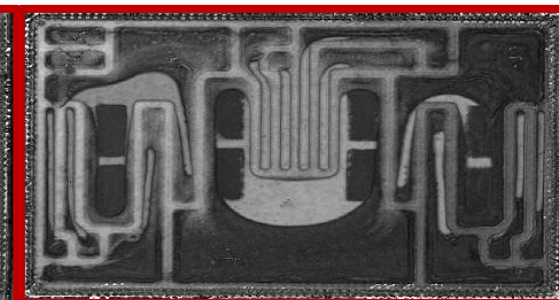
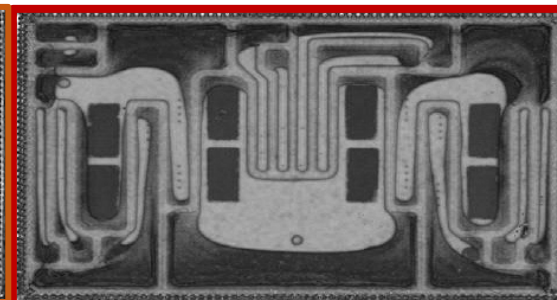
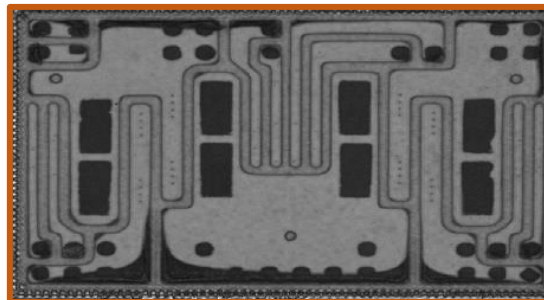
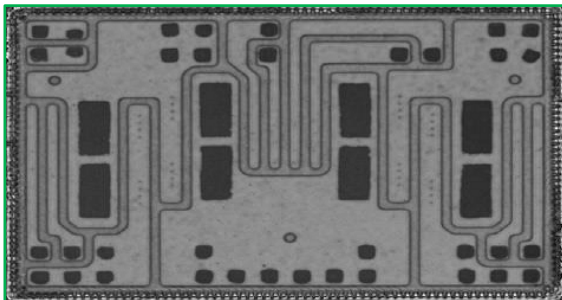
500 Cycles

1000 Cycles

Epoxy



Silicone



Significant difference observed in thermal-shock stressed conchoidal fractures between **Epoxy** and **Silicone**

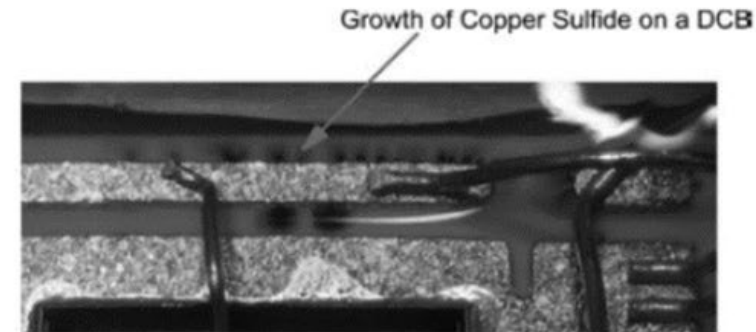
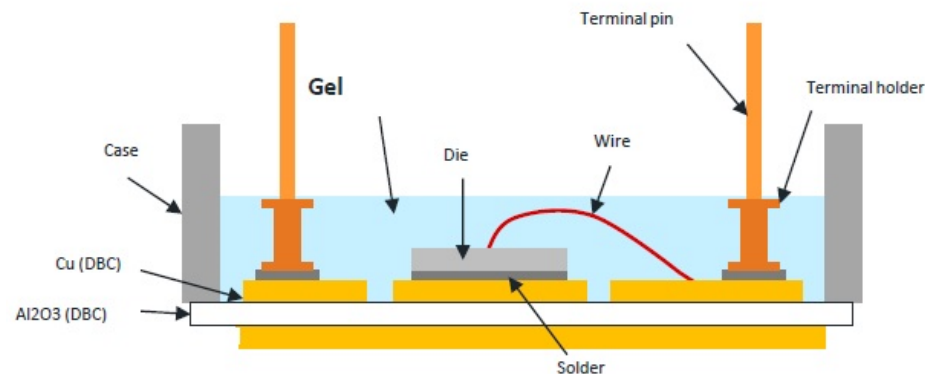
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- **Problem: Temperature Cycling**

- DBC extends and bends with temperature variation, causing conchoidal fractures

- **Problem: Humidity**

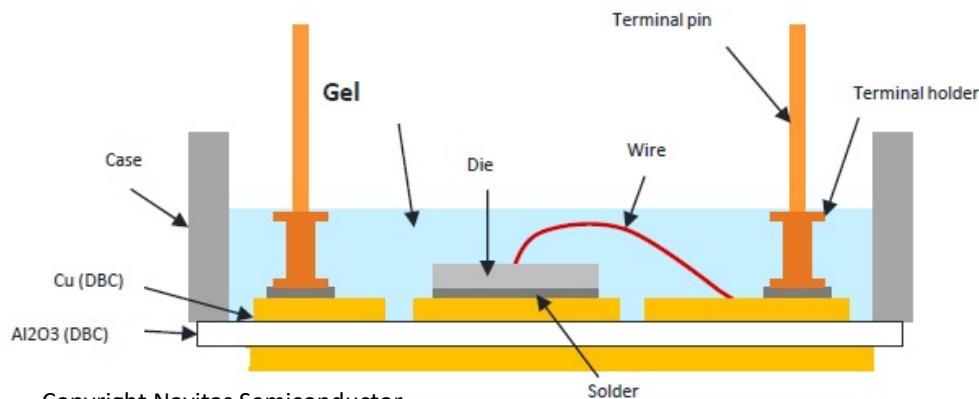
- Silicone gel absorbs moisture and contaminants from the air, leading to short circuit failures



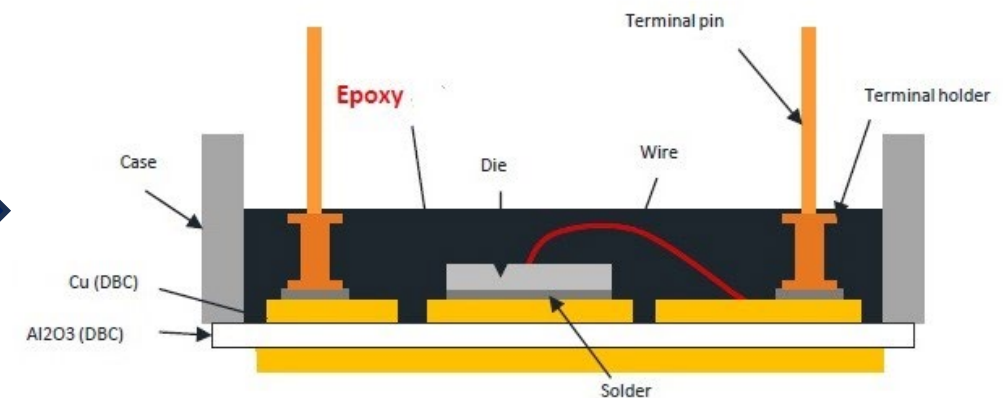
- High temperatures - Moisture and sulphur-containing substances (e.g. hydrogen sulphides) leads to ingression

How Does Epoxy-Resin Solve These Challenges?

- **Reduces variation of plastic strain of bond wires**
 - Epoxy reduces stress between DBC and bond-wires
- **Reduces expansion stresses due to higher thermal conductivity**
 - Epoxy provides ~10x higher thermal conductivity over gel, quickly spreading heat
- **Limits extension and bending of overall structure**
 - Epoxy limits extension and bending of DBC
- **Reduces moisture ingress**
 - Gel absorbs water moisture & contaminants



Gel to Epoxy



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Qualification Tests : Beyond Industry Norms

Test	Reference	Test Conditions	Duration	Devices	Result
HTRB	JESD22-A108	High-Temperature Reverse Bias: $T_j = 175^{\circ}\text{C}$, $V_{DS} = 1200\text{V}$	1000hrs	≥ 77 dies	PASS
HTRB	JESD22-A108	High-Temperature Reverse Bias: $T_j = 175^{\circ}\text{C}$, $V_{DS} = 1200\text{V}$	1000hrs	≥ 6 modules	PASS
HTGB	JESD22-A108	High Temperature Gate Bias: $T_j = 175^{\circ}\text{C}$, $V_{GS} = +22\text{V}$	1000hrs	≥ 77 dies	PASS
HTGBR	JESD22-A108	High Temperature Gate Bias: $T_j = 175^{\circ}\text{C}$, $V_{GS} = -10\text{V}$	1000hrs	≥ 77 dies	PASS
HV-H3TRB	JESD22 A-101	High Humidity High-Temperature Bias: 85°C , 85%RH, $V_{DS} = 960\text{V}$	1000hrs	≥ 77 dies	PASS
HV-H3TRB (THB)	JESD22 A-101	High Humidity High-Temperature Bias: 85°C , 85%RH, $V_{DS} = 960\text{V}$	1000hrs	≥ 6 modules	PASS
TC	JESD22-A104	Temperature Cycle: $-55^{\circ}\text{C} / 150^{\circ}\text{C}$	1000 cyc	≥ 6 modules	PASS
HTSL	JESD22-A103	High-Temperature Storage Life: $T_a = 175^{\circ}\text{C}$	1000hrs	≥ 6 modules	PASS
PC	IEC 60749-34	Power Cycling (sec) : $\Delta T_j = 80^{\circ}\text{C}$, $T_j \text{ max} = 150^{\circ}\text{C}$	25,000 cycles	≥ 6 modules	PASS
VIB	IEC 60068-2-6	Vibration (25-500Hz/15min, 10G, each 2 hours X, Y, Z)	N/A	≥ 6 modules	PASS
UIS	AEC Q101-004	Unclamped Inductive Switching	N/A	≥ 3 modules	PASS

Competition : No THB

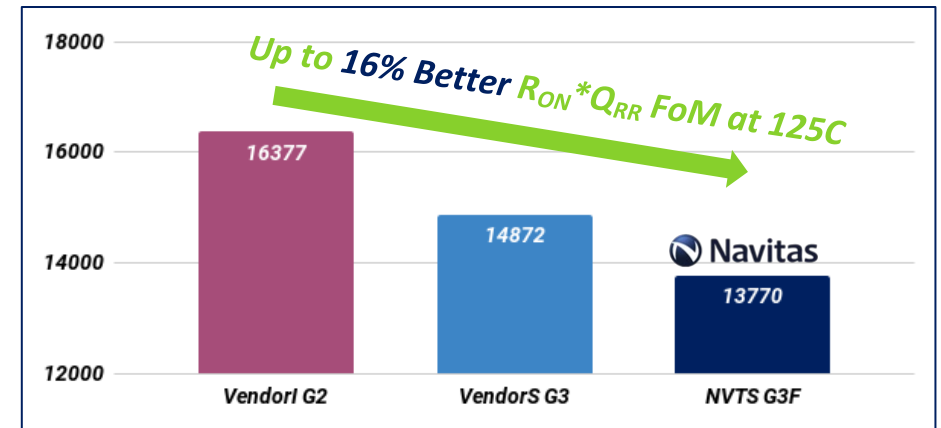
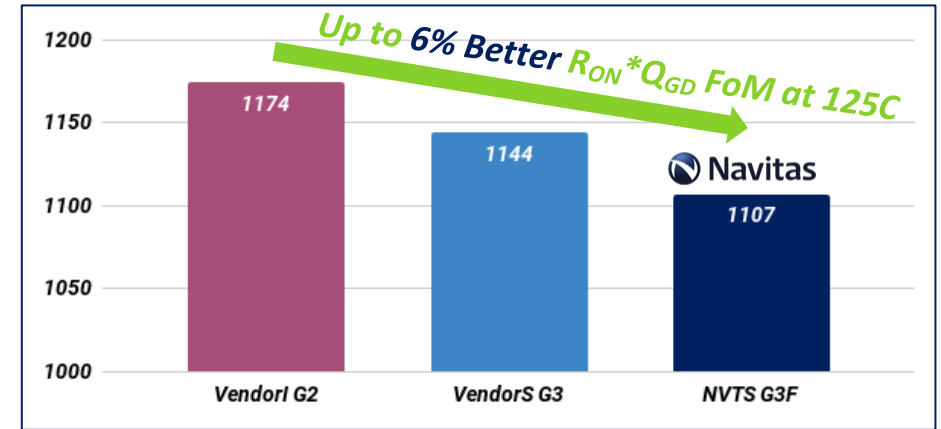
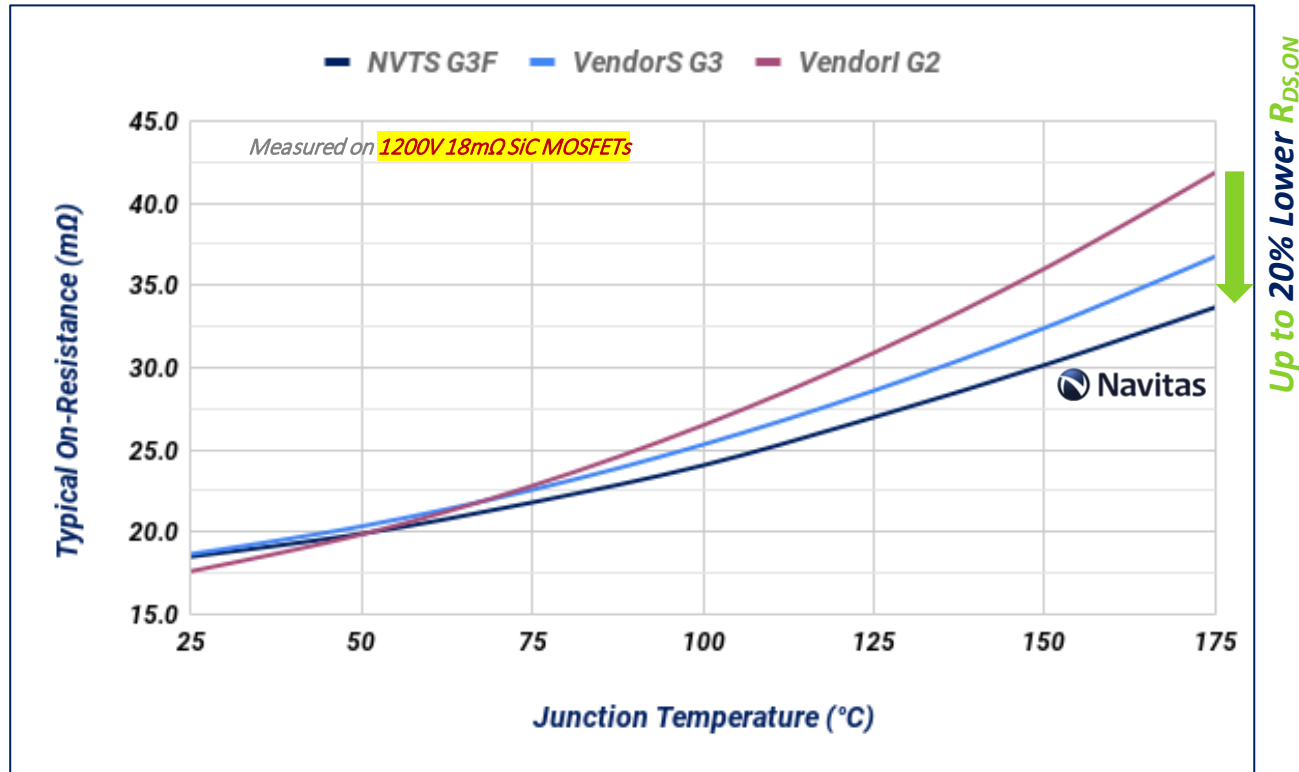
Competition : <100 cycles

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Trench-Assisted Planar = Superior Performance

5% - 20% Lower $R_{DS,ON}$ at 100°C – 175°C



Industry-Leading Performance Enabled by Proprietary Trench-Assisted Planar SiC MOSFET Technology

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Thank you!

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